

10016701_CLS
Most Frequently Occurring Classifications of Patents Returned
From A Search of 10016701 on March 24, 2004

Original Classifications

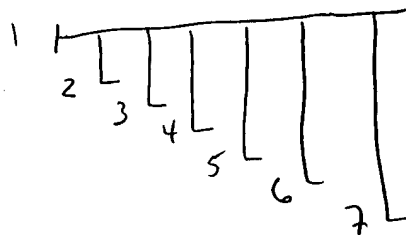
16 714/726
8 714/731
6 714/727
3 714/733
2 324/73.1
2 365/233

Cross-Reference Classifications

7 714/724
7 714/733
4 714/30
4 714/736
3 365/201
3 714/727
3 714/732
2 327/202
2 714/726
2 714/731

Combined Classifications

18 714/726
10 714/731
10 714/733
9 714/727
8 714/724
5 714/736
4 714/30
4 714/732
3 324/73.1
3 365/201
2 327/202
2 365/233
2 714/718
2 714/738
2 716/4



10016701_CLSTITLES

Titles of Most Frequently Occurring Classifications of Patents Returned

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18	714/726	(16 OR, 2 XR)
	Class 714 :	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
	714/699	PULSE OR DATA ERROR HANDLING
	714/724	.Digital logic testing
	714/726	..Scan path testing (e.g., level sensitive scan design (LSSD))
10	714/731	(8 OR, 2 XR)
	Class 714 :	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
	714/699	PULSE OR DATA ERROR HANDLING
	714/724	.Digital logic testing
	714/726	..Scan path testing (e.g., level sensitive scan design (LSSD))
	714/731	...Clock or synchronization
10	714/733	(3 OR, 7 XR)
	Class 714 :	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
	714/699	PULSE OR DATA ERROR HANDLING
	714/724	.Digital logic testing
	714/733	..Built-in testing circuit (BILBO)
9	714/727	(6 OR, 3 XR)
	Class 714 :	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
	714/699	PULSE OR DATA ERROR HANDLING
	714/724	.Digital logic testing
	714/726	..Scan path testing (e.g., level sensitive scan design (LSSD))
	714/727	...Boundary scan
8	714/724	(1 OR, 7 XR)
	Class 714 :	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
	714/699	PULSE OR DATA ERROR HANDLING
	714/724	.Digital logic testing
5	714/736	(1 OR, 4 XR)

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Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY

714/699 PULSE OR DATA ERROR HANDLING

714/724 .Digital logic testing

714/736 ..Device response compared to expected
fault-free response

4 714/30 (0 OR, 4 XR)

Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY

714/100 DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING

714/1 .Reliability and availability

714/25 ..Fault locating (i.e., diagnosis or testing)

714/27 ...Particular access structure

714/30Built-in hardware for diagnosing or testin
g
within-system component (e.g., microprocess
or test mode
circuit, scan path)

4 714/732 (1 OR, 3 XR)

Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY

714/699 PULSE OR DATA ERROR HANDLING

714/724 .Digital logic testing

714/732 ..Signature analysis

3 324/73.1 (2 OR, 1 XR)

Class 324 : ELECTRICITY: MEASURING AND TESTING

324/73.1 PLURAL, AUTOMATICALLY SEQUENTIAL TESTS

3 365/201 (0 OR, 3 XR)

Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL

365/189.01 READ/WRITE CIRCUIT

365/201 .Testing

2 327/202 (0 OR, 2 XR)

Class 327 : MISCELLANEOUS ACTIVE ELECTRICAL NONLINEAR
DEVICES, CIRCUITS, AND SYSTEMS

327/100 SIGNAL CONVERTING, SHAPING, OR GENERATING

327/185 .Particular stable state circuit (e.g.,
tristable, etc.)

327/199 ..Circuit having only two stable states (i.e.,
bistable)

327/202 ...Master-slave bistable latch

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- 2 365/233 (2 OR, 0 XR)
 - Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL
 - 365/230.01 ADDRESSING
 - 365/233 .Sync/clocking

- 2 714/718 (1 OR, 1 XR)
 - Class 714 : ERROR DETECTION/CORRECTION AND FAULT
 - DETECTION/RECOVERY
 - 714/699 PULSE OR DATA ERROR HANDLING
 - 714/718 .Memory testing

- 2 714/738 (1 OR, 1 XR)
 - Class 714 : ERROR DETECTION/CORRECTION AND FAULT
 - DETECTION/RECOVERY
 - 714/699 PULSE OR DATA ERROR HANDLING
 - 714/724 .Digital logic testing
 - 714/738 ..Including test pattern generator

- 2 716/4 (1 OR, 1 XR)
 - Class 716 : DATA PROCESSING: DESIGN AND ANALYSIS OF
 - CIRCUIT OR SEMICONDUCTOR MASK
 - 716/1 CIRCUIT DESIGN
 - 716/4 .Testing or evaluating

10016701_LIST

PLUS Search Results for S/N 10016701, Searched March 24, 2004

The Patent Linguistics Utility System (PLUS) is a USPTO automated search system for U.S. Patents from 1971 to the present. PLUS is a query-by-example search system which produces a list of patents that are most closely related linguistically to the application searched. This search was prepared by the staff of the Scientific and Technical Information Center, SIRA.

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